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- Combines 'F245 and 'F280B Functions in One Package
- High-Impedance N-P-N Inputs for Reduced Loading (70 μA in Low and High States)
- High Output Drive and Light Bus Loading
- 3-State B Outputs Sink 64 mA and Source 15 mA
- Input Diodes for Termination Effects
- Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs

description

The SN74F657 contains eight noninverting buffers with 3-state outputs and an 8-bit parity generator/checker. It is intended for bus-oriented applications. The buffers have a specified current sinking capability of 24 mA at the A port and 64 mA at the B port.



The transmit/receive (T/\overline{R}) input determines the direction of the data flow through the bidirectional transceivers. When T/\overline{R} is high, data is transmitted from the A port to the B port. When T/\overline{R} is low, data is received at the A port from the B port.

When the output enable (\overline{OE}) input is high, both the A and B ports are placed in a high-impedance state (disabled). The ODD/EVEN input allows the user to select between odd or even parity systems. When transmitting from A port to B port $(T/\overline{R} \text{ high})$, PARITY is an output from the generator/checker. When receiving from B port to A port $(T/\overline{R} \text{ low})$, PARITY is an input.

When transmitting (T/R high), the parity select (ODD/EVEN) input is made high or low as appropriate. The A port is then polled to determine the number of high bits. The PARITY output goes to the logic state determined by ODD/EVEN and the number of high bits on A port. When ODD/EVEN is low (for even parity) and the number of high bits on A port is odd, the PARITY will be high, transmitting even parity. If the number of high bits on A port is even, the PARITY will be low, keeping even parity.

When in the receive mode (T/R low), the B port is polled to determine the number of high bits. If ODD/ \overline{EVEN} is low (for even parity) and the number of highs on B port is:

- 1. Odd and the PARITY input is high, then ERR will be high signifying no error.
- 2. Even and the PARITY input is high, then ERR will be low indicating an error.

The SN74F657 is characterized for operation from 0°C to 70°C.

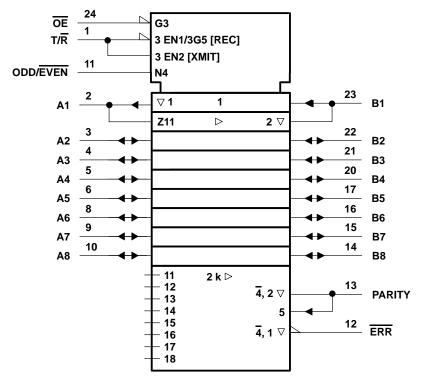


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FUNCTION TABLE

NUMBER OF A OR B	INPUTS			INPUT/OUTPUT	OUTPUTS		
INPUTS THAT ARE HIGH	OE	T/R	ODD/EVEN	PARITY	ERR	OUTPUT MODE	
	L	Н	Н	Н	Z	Transmit	
	L	Н	L	L	Z	Transmit	
02469	L	L	Н	Н	Н	Receive	
0, 2, 4, 6, 8	L	L	Н	L	L	Receive	
	L	L	L	Н	L	Receive	
	L	L	L	L	Н	Receive	
	L	Н	Н	L	Z	Transmit	
	L	Н	L	Н	Z	Transmit	
1 2 5 7	L	L	Н	Н	L	Receive	
1, 3, 5, 7	L	L	Н	L	Н	Receive	
	L	L	L	Н	Н	Receive	
	L	L	L	L	L	Receive	
Don't care	Н	Х	Х	Z	Z	Z	

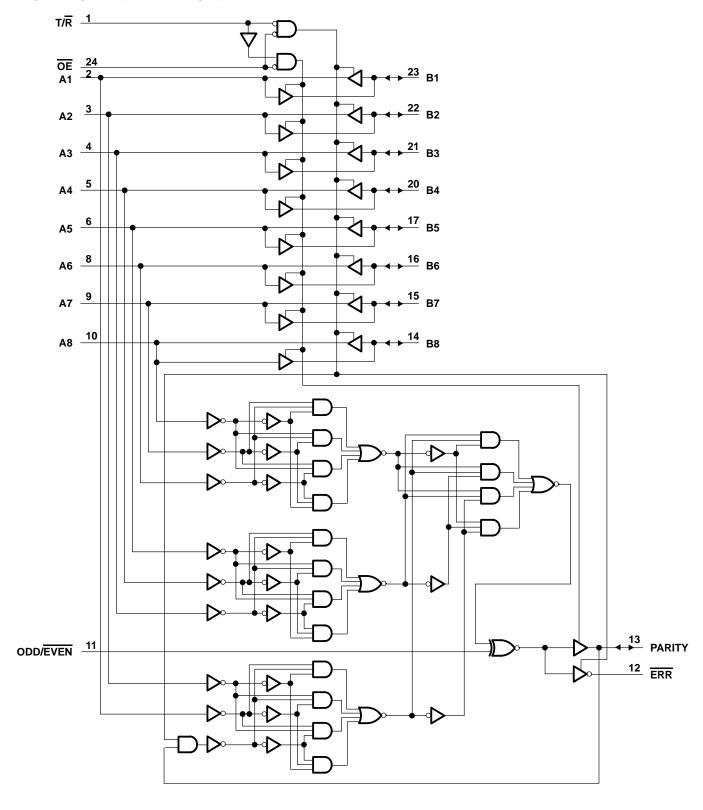
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (excluding I/O ports) (see Note 1)	1.2 V to 7 V
Input current range	
Voltage range applied to any output in the disabled or power-off state	0.5 V to 5.5 V
Voltage range applied to any output in the high state	-0.5 V to V_{CC}
Current into any output in the low state: A1-A8	48 mA
B1-B8	128 mA
Operating free-air temperature range	0°C to 70°C
Storage temperature range	65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

				MIN	NOM	MAX	UNIT
VCC	Supply voltage			4.5	5	5.5	V
VIH	High-level input voltage			2			V
V _{IL}	Low-level input voltage					0.8	V
lau	High-level output current		A1-A8			-3	mA
ЮН			B1-B8, PARITY, ERR			- 12	
IOL	Low-level output current		A1-A8			24	mA
			B1-B8, PARITY, ERR			64	
TA	Operating free-air temperature			0		70	°C

NOTE 1: The input-voltage ratings may be exceeded provided the input-current ratings are observed.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST CONDITION	NS	MIN	TYP [†]	MAX	UNIT
٧ıĸ		$V_{CC} = 4.5 \text{ V},$	I _I = – 18 mA				- 1.2	V
Vон	Any output	$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -3 \text{ mA}$		2.4	3.3		
	B1-B8, PARITY, ERR	$V_{CC} = 4.5 \text{ V},$	I _{OH} = – 15 mA		2	3.1		V
	Any output	$V_{CC} = 4.75 \text{ V},$	I _{OH} = – 1 mA to –	- 3 mA	2.7			
V _{OL}	A1-A8	V _{CC} = 4.5 V	$I_{OL} = 24 \text{ mA}$			0.35	0.5	V
	B1-B8, PARITY, ERR		I _{OL} = 64 mA			0.42	0.55	V
	T/R	V _{CC} = 0,	V _I = 7 V,	OE = 4.5 V			0.1	mA
	ŌĒ	$V_{CC} = 0$,	V _I = 7 V,	T/R = 4.5 V			0.1	
l _l	ODD/EVEN	$V_{CC} = 0$,	V _I = 7 V				0.1	
	A1-A8	V _{CC} = 5.5 V,					2	
	B1-B8		V _I = 7 V				1	
	A, B, PARITY	V _{CC} = 5.5 V,	V _I = 2.7 V				70	
I _{IH} ‡	T/R, OE						40	μΑ
	ODD/EVEN]					20	
	A, B, PARITY	V _{CC} = 5.5 V,	V _I = 0.5 V				- 70	
I _{IL} ‡	T/R, OE						- 40	μΑ
	ODD/EVEN						- 20	
	A1-A8	V _{CC} = 5.5 V,	V- 0		- 60		- 150	mA
los§	B1-B8		$V_O = 0$		- 100		- 225	mA
lozh	ERR	V _{CC} = 5.5 V,	V _I = 2.7 V				50	μΑ
lozL	ERR	V _{CC} = 5.5 V,	V _I = 0.5 V				-50	μΑ
Іссн		V _{CC} = 5.5 V				90	125	mA
ICCL		V _{CC} = 5.5 V				106	150	mA
ICCZ		V _{CC} = 5.5 V				98	145	mA

[†] All typical values are at V_{CC} = 5 V, T_A = 25°C.
‡ For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.
§ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

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switching characteristics (see Note 2)

PARAMETER	ADAMETED I		$\begin{array}{c} \text{V}_{\text{CC}} = 5 \text{ V,} \\ \text{C}_{\text{L}} = 50 \text{ pF,} \\ \text{R1} = 500 \ \Omega, \\ \text{(OUTPUT)} \\ \text{R2} = 500 \ \Omega, \\ \text{T}_{\text{A}} = 25^{\circ}\text{C} \end{array}$			$V_{CC} = 4.5$ $C_L = 50 \text{ pF}$ $R1 = 500 \Omega$ $R2 = 500 \Omega$ $T_A = MIN \text{ t}$	UNIT	
			MIN	TYP	MAX	MIN	MAX	
t _{PLH}	A or B	B or A	2.5	4.2	7.5	2.5	8	ns ns
^t PHL	AUID		3	4	7.5	3	8	
^t PLH	А	PARITY	6	8.4	14	6	16	ns
^t PHL			6.8	8.5	15	6.8	16	
^t PLH	ODD/ EVEN	PARITY, ERR	4	6.4	11	4	12	ns
^t PHL		PARII I, ERR	4.5	6.9	11.5	4.5	12.5	115
^t PLH	В	ERR	8	12.7	20.5	7.5	22.5	ns
^t PHL	В	EKK	8	13.4	20.5	7.5	22.5	115
^t PLH	PARITY	ERR	6	8.1	15.5	6	16.5	ns
^t PHL			7.5	8.8	15.5	7.5	17	
^t PZH	ŌĒ	4 B B4BITY 500 †	3	5.3	8	3	9	
t _{PZL}		A, B, PARITY, or ERR‡	4	5.4	9.5	4	11	ns
t _{PHZ}	ŌĒ	A, B, PARITY, or ERR‡	2	4.2	7.5	2	8	ns
t _{PLZ}		A, D, FANTI I, UI ERR+	2	3.7	6	2	6.5	

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 2: Load circuits and waveforms are shown in Section 1.



[‡] These delay times reflect the 3-state recovery time only and not the signal through the buffers or parity check circuitry. To assure valid information at the ERR output pin, time must be allowed for the signal to propagate through the drivers (B to A), and to the ERR output. Valid data at the ERR output is greater than or equal to (B to A) + (A to PARITY).

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